

## Message Text

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42

ACTION EB-07

INFO OCT-01 CIAE-00 COME-00 DODE-00 NSAE-00 MC-02 ACDA-05

TRSE-00 EUR-12 ERDA-05 ISO-00 EA-06 ERDE-00 /038 W

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P 131529Z MAR 75

FM USMISSION OECD PARIS

TO SECSTATE WASH DC PRIORITY 5932

C O N F I D E N T I A L OECD PARIS 06451

EXCON

E.O. 11652: XGDS1

TAGS: ESTC, COCOM

SUBJECT: COCOM LIST REVIEW: IL 1544 - SEMICONDUCTOR  
DIODES AND TRANSISTORS

REFS: A. COCOM DOC REV (74) 1544/1

B. OECD PARIS 27175, 11/15/74

C. COCOM DOC REV (74) 1544/2

1. REF C IS UK MEMO CIRCULATED MARCH 13 READING  
AS FOLLOWS:

A. PARAGRAPH 32 OF COCOM DOC REV (74)1544/1 RECORDS  
THAT THE UNITED KINGDOM DELEGATION UNDERTOOK  
TO GIVE FURTHER STUDY TO A NETHERLANDS PROPOSAL THAT  
NOTE 3 OF THE UNITED KINGDOM COUNTER PROPOSAL ON THIS  
ITEM IN COCOM DOC REV (74)5 SHOULD REFER TO THE STAN-  
DARDS OF THE INTERNATIONAL ELECTROTECHNICAL COMMITTEE  
RATHER THAN TO THE DATA BOOK.

B. THE UNITED KINGDOM AUTHORITIES BELIEVE THAT THE FI-  
GURE OF MERIT DEFINED IN THE DATA BOOK IS IN SUCH COMMON  
USE THAT IT WOULD BE THE MOST APPROPRIATE REFERENCE.  
THEY ACCORDINGLY PROPOSE TO QUOTE IT VERBATIM. NOTE 3  
WOULD THEN READ AS FOLLOWS:

"3. THE FIGURE OF MERIT Q IS DEFINED AS:

F-SUB-M DIVIDED BY THE PRODUCT OF 2 PI, R-SUB-S, AND

C-SUB-J WHERE F-SUB-M IS THE TEST FREQUENCY, R-SUB-S

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EQUALS SERIES RESISTANCE AND C-SUB-J EQUALS JUNCTION

CAPACITANCE".

2. NARRATIVE FORMULA ABOVE NATURALLY APPEARS IN CONVENTIONAL ALGEBRAIC NOTATION IN THE DOCUMENT.

3. ACTION REQUESTED: INSTRUCTIONS BY MARCH 18, WHEN THIS ITEM IS TO BE DISCUSSED IN ROUND II.  
TURNER

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NNN

## Message Attributes

**Automatic Decaptioning:** X  
**Capture Date:** 01 JAN 1994  
**Channel Indicators:** n/a  
**Current Classification:** UNCLASSIFIED  
**Concepts:** STRATEGIC TRADE CONTROLS, EXCEPTIONS LIST, SEMICONDUCTOR DEVICES  
**Control Number:** n/a  
**Copy:** SINGLE  
**Draft Date:** 13 MAR 1975  
**Decaption Date:** 01 JAN 1960  
**Decaption Note:**  
**Disposition Action:** RELEASED  
**Disposition Approved on Date:**  
**Disposition Authority:** GarlanWA  
**Disposition Case Number:** n/a  
**Disposition Comment:** 25 YEAR REVIEW  
**Disposition Date:** 28 MAY 2004  
**Disposition Event:**  
**Disposition History:** n/a  
**Disposition Reason:**  
**Disposition Remarks:**  
**Document Number:** 1975OECDP06451  
**Document Source:** CORE  
**Document Unique ID:** 00  
**Drafter:** n/a  
**Enclosure:** n/a  
**Executive Order:** X1  
**Errors:** N/A  
**Film Number:** D750088-0463  
**From:** OECD PARIS  
**Handling Restrictions:** n/a  
**Image Path:**  
**ISecure:** 1  
**Legacy Key:** link1975/newtext/t19750354/aaaabwog.tel  
**Line Count:** 69  
**Locator:** TEXT ON-LINE, ON MICROFILM  
**Office:** ACTION EB  
**Original Classification:** CONFIDENTIAL  
**Original Handling Restrictions:** n/a  
**Original Previous Classification:** n/a  
**Original Previous Handling Restrictions:** n/a  
**Page Count:** 2  
**Previous Channel Indicators:** n/a  
**Previous Classification:** CONFIDENTIAL  
**Previous Handling Restrictions:** n/a  
**Reference:** 75 COCOM DOC REV (71544/1  
**Review Action:** RELEASED, APPROVED  
**Review Authority:** GarlanWA  
**Review Comment:** n/a  
**Review Content Flags:**  
**Review Date:** 13 MAY 2003  
**Review Event:**  
**Review Exemptions:** n/a  
**Review History:** RELEASED <13 MAY 2003 by ElyME>; APPROVED <17 JUN 2003 by GarlanWA>  
**Review Markings:**

Margaret P. Grafeld  
Declassified/Released  
US Department of State  
EO Systematic Review  
05 JUL 2006

**Review Media Identifier:**  
**Review Referrals:** n/a  
**Review Release Date:** n/a  
**Review Release Event:** n/a  
**Review Transfer Date:**  
**Review Withdrawn Fields:** n/a  
**Secure:** OPEN  
**Status:** NATIVE  
**Subject:** COCOM LIST REVIEW: IL 1544 - SEMICONDUCTOR DIODES AND TRANSISTORS  
**TAGS:** ESTC, US, COCOM  
**To:** STATE  
**Type:** TE  
**Markings:** Margaret P. Grafeld Declassified/Released US Department of State EO Systematic Review 05 JUL 2006